

# **IGBT Chip in NPT-technology**

### Features:

- 1700V NPT technology
- 280µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling
- Qualified according to JEDEC for target applications

### Recommended for:

· chip only

# **Applications:**

drives



Chip Type	<b>V</b> <sub>CE</sub>	<i>I</i> <sub>Cn</sub>	Die Size	Package
SIGC185T170R2C	1700V	100A	13.56 x 13.56 mm <sup>2</sup>	sawn on foil

### **Mechanical Parameters**

Die size		13.56 x 13.56		
Emitter pad size (incl. gate pad)		See chip drawing		
Gate pad size		0.757 x 1.48		
Area total		183.87		
Thickness		280	μm	
Wafer size		150	mm	
Max.possible chips pe	er wafer	72		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, <500μm		
Reject ink dot size		Ø 0.65mm ; max 1.2mm		
Ctorono anvironment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month		
Storage environment	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 month		



## **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, T <sub>vj</sub> =25 °C	V <sub>CE</sub>	1700	V
DC collector current, limited by $T_{\rm vjmax}$	Ic	1)	А
Pulsed collector current, $t_p$ limited by $T_{vj \max}^{2}$	I <sub>c,puls</sub>	300	А
Gate emitter voltage	$V_{\rm GE}$	±20	V
Operating junction and storage temperature	$T_{vj}$ , $T_{stg}$	-55 +150	°C
Short circuit data $^{2)3)}$ $V_{GE} = 15V$ , $V_{CC} = 1000V$ , $T_{vj} = 150$ °C	t <sub>SC</sub>	10	μs

<sup>1)</sup> depending on thermal properties of assembly

# Static Characteristics (tested on wafer), $T_{vj}$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter			min.	typ.	max.	
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	$V_{\rm GE}$ =0V , $I_{\rm C}$ =2 mA	1700			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, I <sub>C</sub> =100A	2.18	2.6	2.92	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =4.4mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.6	5.5	6.4	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1700V , V <sub>GE</sub> =0V			3.8	μA
Gate-Emitter leakage current	I <sub>GES</sub>	$V_{\text{CE}}$ =0V , $V_{\text{GE}}$ =20V			480	nA
Integrated gate resistor	$r_{\rm G}$			2.5		Ω

## Electrical Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
raidilletei			min.	typ.	max.	Oiiit
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	$V_{\text{GE}}$ =15V, $I_{\text{C}}$ =100A, $T_{\text{vj}}$ =125 °C		3.1		V
Input capacitance	C <sub>ies</sub>	$V_{\text{CE}} = 25\text{V},$ $V_{\text{GE}} = 0\text{V}, f = 1\text{MHz}$		15000		pF
Reverse transfer capacitance	C <sub>res</sub>	$T_{\rm vj}$ =25 °C		700		F .

<sup>&</sup>lt;sup>2)</sup> not subject to production test - verified by design/characterization

<sup>&</sup>lt;sup>3)</sup> allowed number of short circuits: <1000; time between short circuits: >1s.



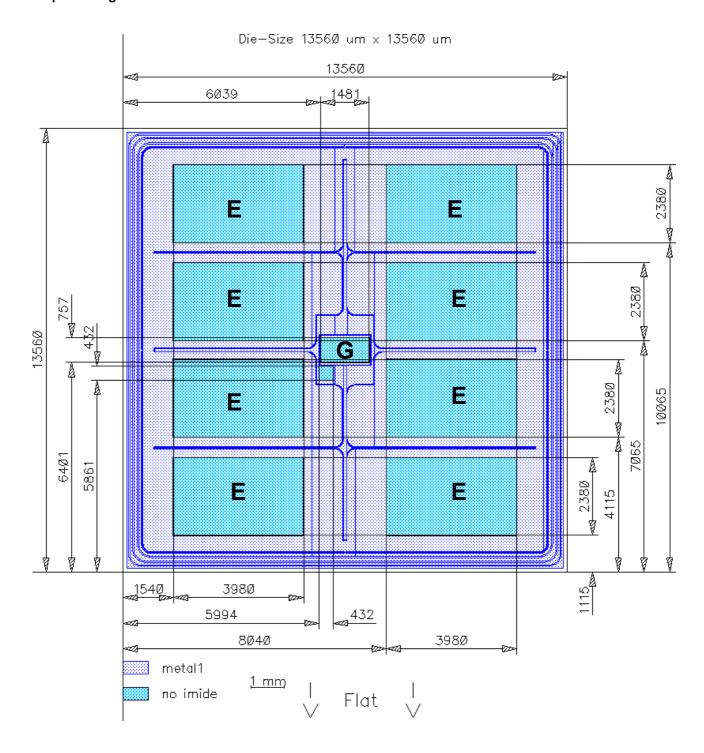
### **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

This chip data sheet refers to the device data sheet	FZ800R17KF6C_B2 Rev.2.1	04.04.2013
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# **Chip Drawing**



**E** = Emitter

**G** = Gate



#### **Description**

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

### **Revision History**

Version	Subjects (major changes since last revision)	Date
2.2	Operating junction and storage temperature	15.05.2013

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